



SEMI®
International
Standards

PV SILICON MATERIALS TASK FORCE
SEMICON EUROPE
ICM, MUNICH

Tuesday, November 12, 2019

11:30 – 12:30

Leader: P. Wagner (self)

Agenda

- | | |
|---|-------|
| 1. Introductions | 11:30 |
| Anti-trust Reminder | |
| Patentable Technologies Guidelines | |
| International Effective Meeting Guidelines | |
| 2. Agenda Review | 11:35 |
| 3. Ballot Review | 11:40 |
| 3.1. 5-year re-approval of | |
| 3.1.1. SEMI PV42, Test Method for In-Line Measurement of Waviness of PV Silicon Wafers by a Light Sectioning Technique Using Multiple Line Segments | |
| 3.1.2. SEMI PV51, Test Method for In-Line Characterization of Photovoltaic Silicon Wafers by Using Photoluminescence | |
| 3.1.3. SEMI PV52, Test Method for In-Line Characterization of Photovoltaic Silicon Wafers Regarding Grain Size | |
| 4. New Business / Action Item Review / Recommendations | 12:10 |
| 5. Next Meeting | 12:20 |
| 6. Adjournment | 12:30 |

Agenda may change without further notice. Please check SEMI's web site.

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